

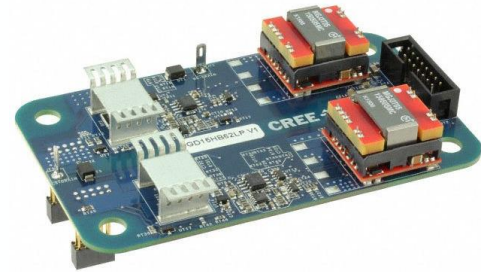


# CAS325M12HM2 Short Circuit

November 2019

# Short Circuit Test Summary

- Paired CAS325M12HM2 module with unmodified CGD15HB62LP gate driver.
- Placed copper sheet across high-side position on short circuit, clamped inductive load test fixture
- Conducted 10 short circuit events on six modules:
  - Three modules at 600 V bus
  - Three modules at 800 V bus
- Compared module parameters before and after short circuit testing
- No parameter shift observed after 10 short circuit events when paired with CGD15HB62LP.



# Short Circuit Test Setup

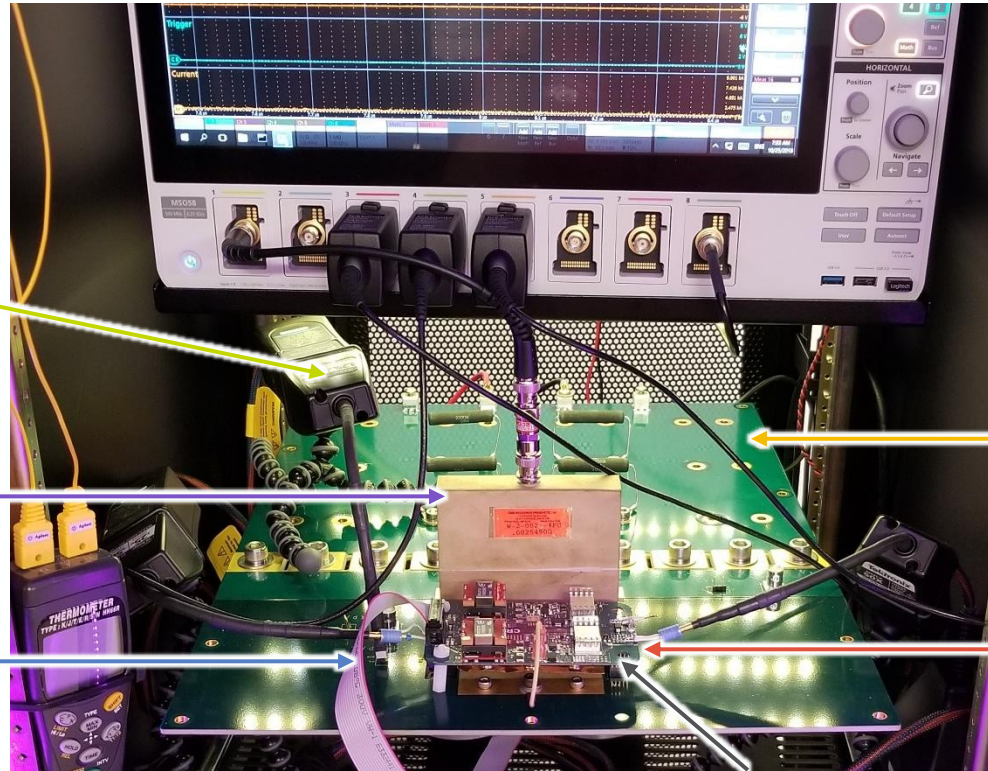
High-Bandwidth,  
Optically Isolated Probe  
(Tektronix IsoVu)

T&M Research  
Current Shunt

Driver input cable  
(Differential signal until it  
reaches controller)

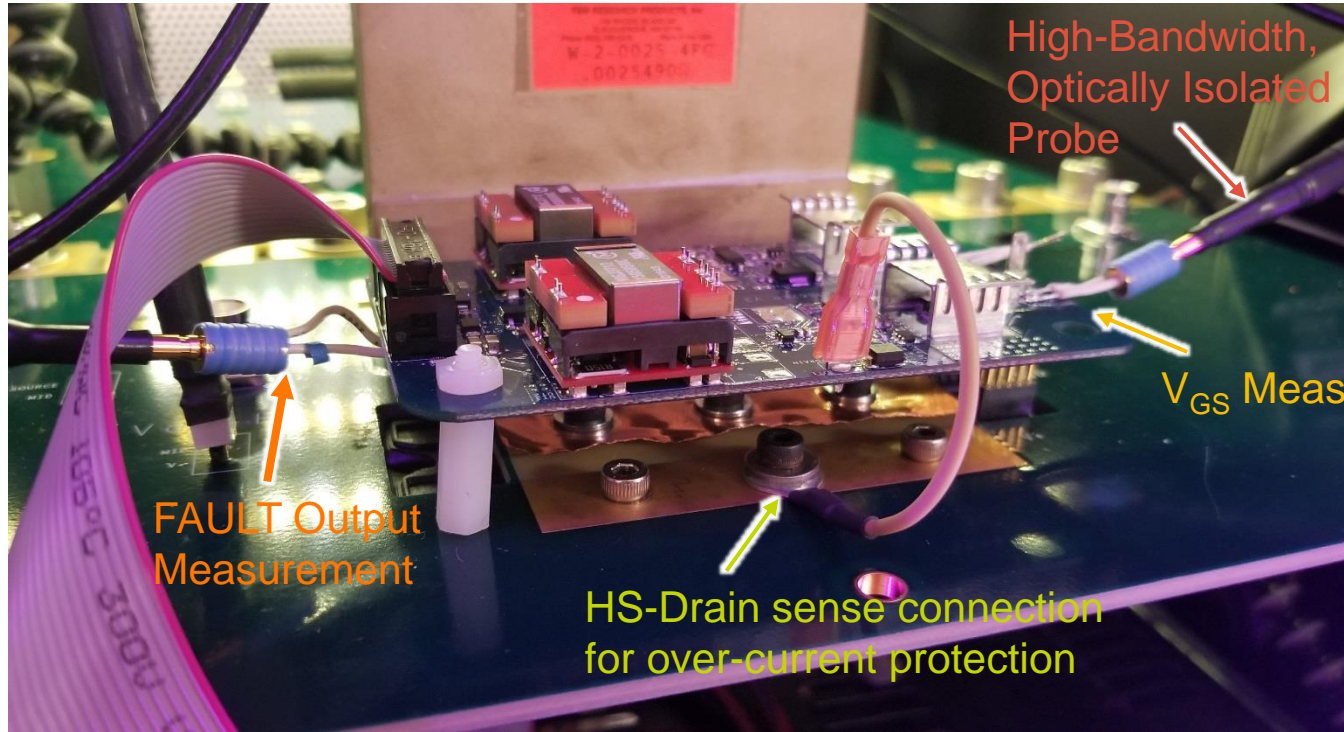
Capacitor  
Bank

Gate Driver

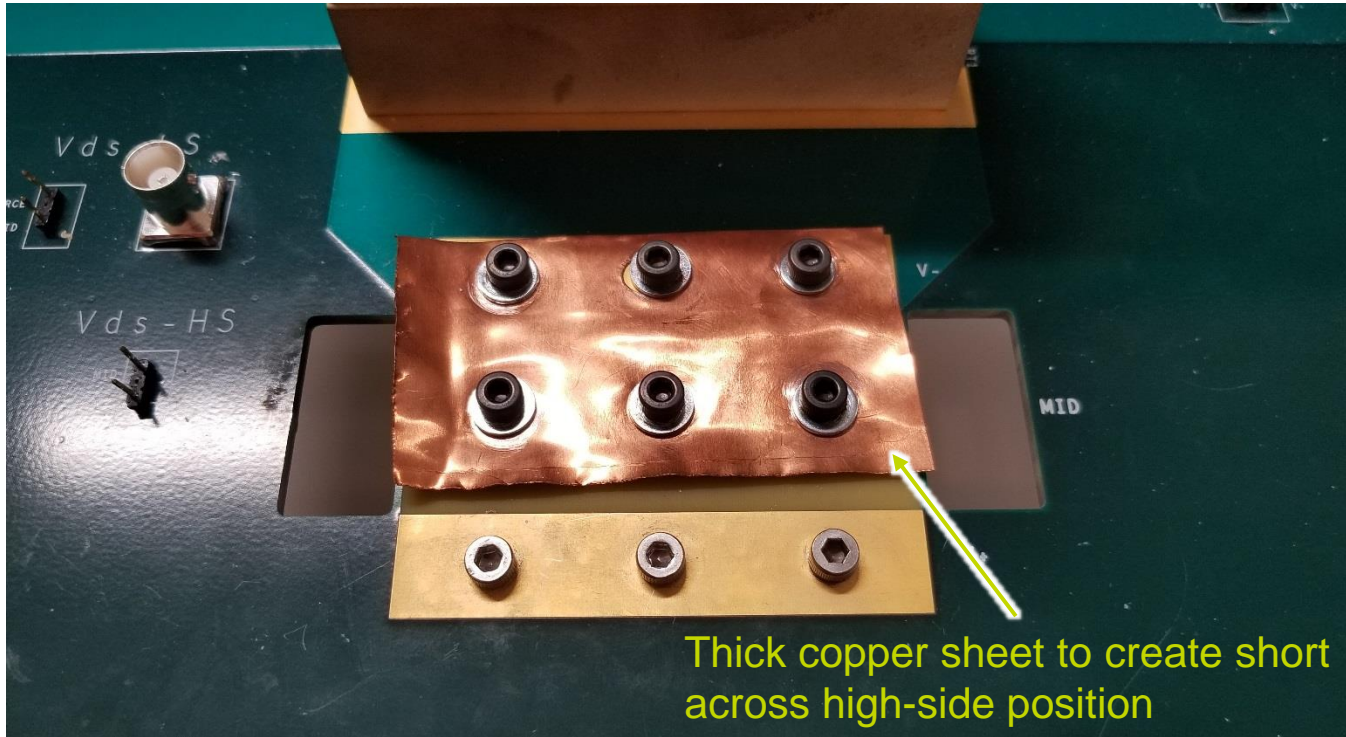


DUT (under PCB)

# Gate Driver Connections



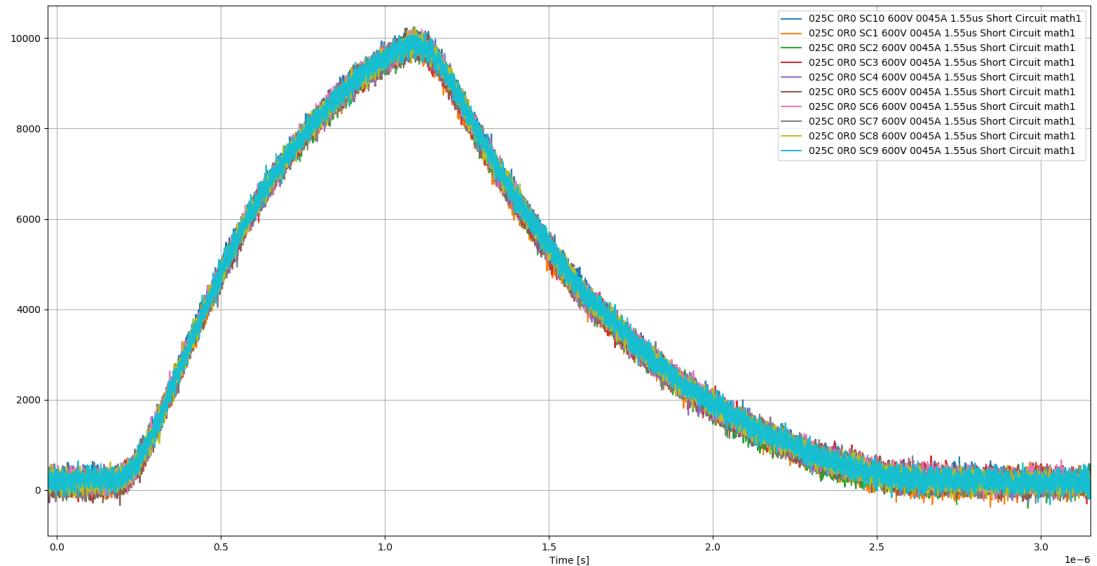
# Short Circuit Condition



# Short Circuit Test Plan

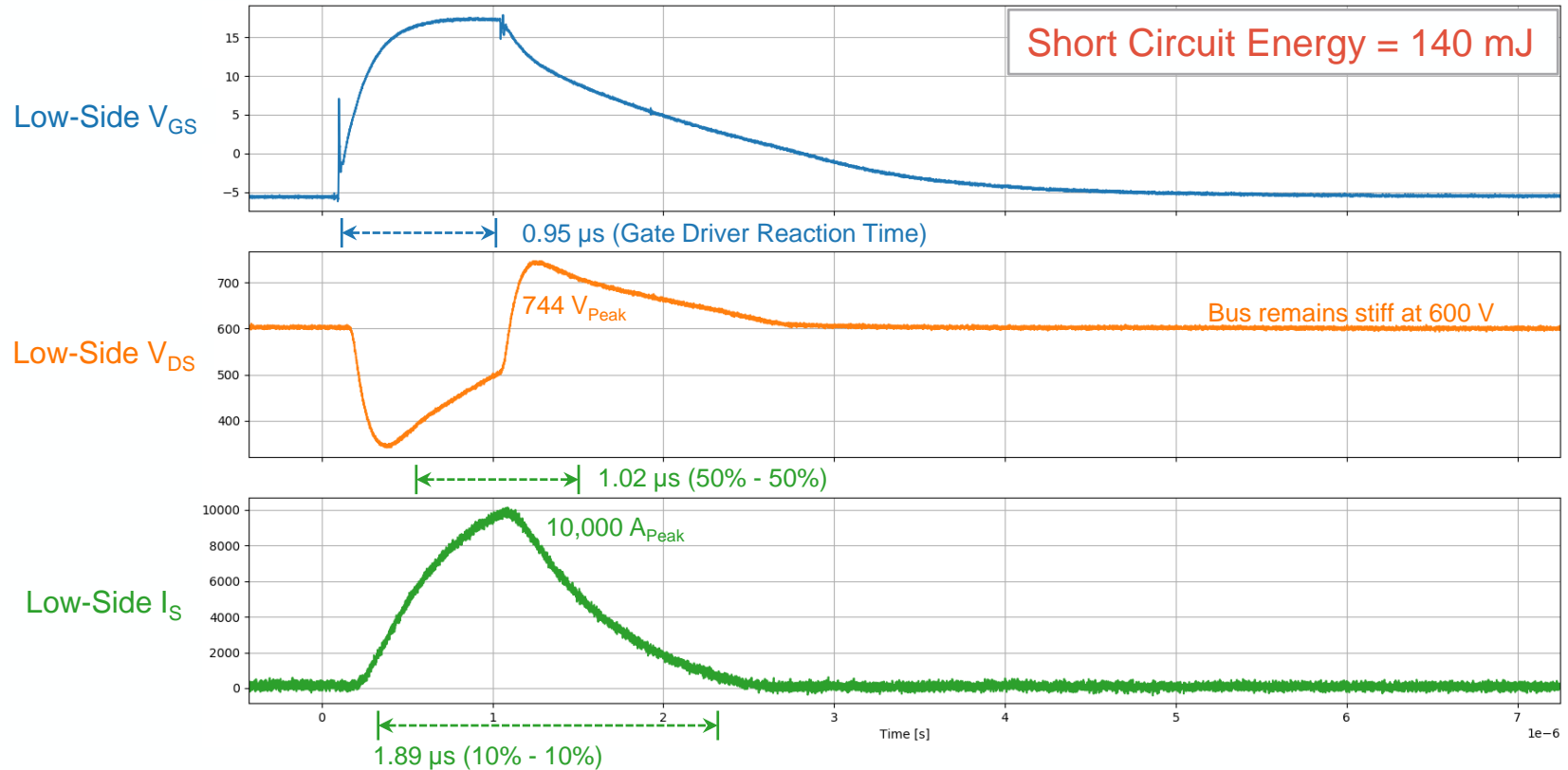
## Test Flow

1. Characterize six CAS325M12HM2
2. Conduct 10 short circuit events on three of the modules at 600 V
3. Conduct 10 short circuit events the other three modules at 800 V
4. Re-characterize the six modules
5. Compare parameter variation

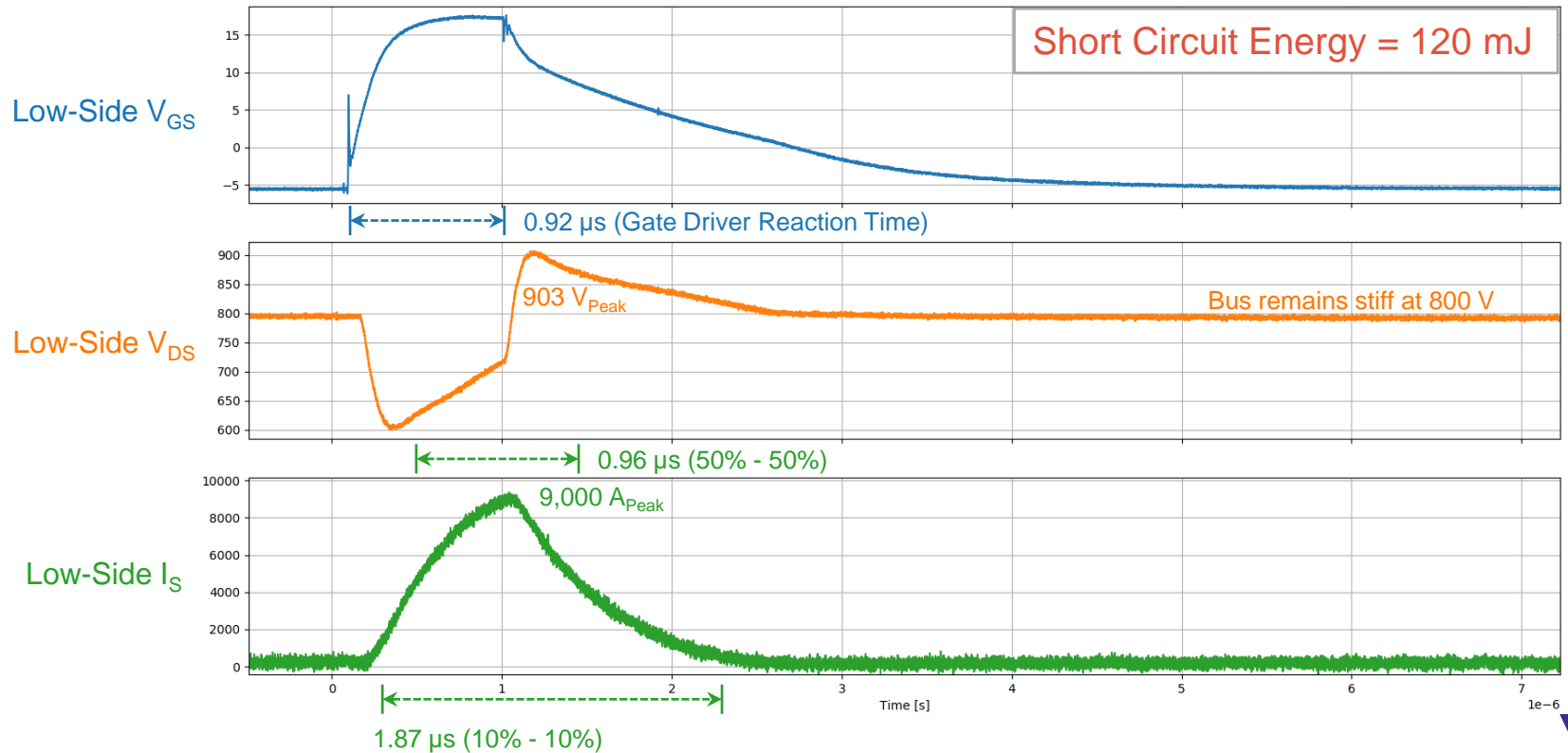


10 Short Circuit Events on one CAS325M12HM2

# Short Circuit Timing (600 V)



# Short Circuit Timing (800 V)





# Module Parameter Comparison

- Almost no change is observed after ten short circuit events are performed on each module.

Before				After					
Diode Connected Threshold				Diode Connected Threshold					
Device	Vds	Threshold	Pass/Fail	Device	Vds	Threshold	Pass/Fail	Difference	% Difference
5349417017_SW1	10	2.82	PASS	5349417017_SW1	10	2.82	PASS	3.16E-03	0%
5349417017_SW2	10	2.62	PASS	5349417017_SW2	10	2.63	PASS	7.82E-03	0%
5349417047_SW1	10	2.89	PASS	5349417047_SW1	10	2.89	PASS	1.52E-03	0%
5349417047_SW2	10	2.76	PASS	5349417047_SW2	10	2.76	PASS	-3.16E-03	0%
5349417070_SW1	10	2.60	PASS	5349417070_SW1	10	2.60	PASS	-4.76E-03	0%
5349417070_SW2	10	2.42	PASS	5349417070_SW2	10	2.42	PASS	-2.98E-03	0%
Rdson				Rdson					
Device	Id	Rdson	Pass/Fail	Device	Id	Rdson	Pass/Fail		
5349417017_SW1	338.27	3.76E-03	PASS	5349417017_SW1	338.29	3.74E-03	PASS	-2.39E-05	-1%
5349417017_SW2	338.23	3.87E-03	PASS	5349417017_SW2	338.328	3.85E-03	PASS	-1.44E-05	0%
5349417047_SW1	338.134	3.78E-03	PASS	5349417047_SW1	338.312	3.76E-03	PASS	-2.21E-05	-1%
5349417047_SW2	338.244	3.80E-03	PASS	5349417047_SW2	338.28	3.78E-03	PASS	-1.16E-05	0%
5349417070_SW1	338.296	3.74E-03	PASS	5349417070_SW1	338.244	3.73E-03	PASS	-1.69E-05	0%
5349417070_SW2	338.328	3.67E-03	PASS	5349417070_SW2	338.33	3.65E-03	PASS	-1.27E-05	0%
Diode On-state				Diode On-state					
Device	Is	Vsd	Pass/Fail	Device	Is	Vsd	Pass/Fail		
5349417017_SW1	348.17	1.58	PASS	5349417017_SW1	349.92	1.58	PASS	-8.00E-04	0%
5349417017_SW2	348.4	1.58	PASS	5349417017_SW2	350.146	1.58	PASS	1.70E-03	0%
5349417047_SW1	348.678	1.63	PASS	5349417047_SW1	349.77	1.63	PASS	-1.00E-03	0%
5349417047_SW2	347.43	1.64	PASS	5349417047_SW2	348.978	1.64	PASS	2.80E-03	0%
5349417070_SW1	347.864	1.61	PASS	5349417070_SW1	349.69	1.61	PASS	5.00E-04	0%
5349417070_SW2	347.348	1.63	PASS	5349417070_SW2	349.818	1.63	PASS	9.00E-04	0%
1200V Rev Leakage				1200V Rev Leakage					
Device	Vds	Id	Pass/Fail	Device	Vds	Id	Pass/Fail		
5349417017_SW1	1200	1.73E-05	PASS	5349417017_SW1	1200	1.70E-05	PASS	-3.42E-07	-2%
5349417017_SW2	1200	2.39E-05	PASS	5349417017_SW2	1200	2.19E-05	PASS	-1.99E-06	-9%
5349417047_SW1	1200	1.87E-05	PASS	5349417047_SW1	1200	1.85E-05	PASS	-1.35E-07	-1%
5349417047_SW2	1200	2.15E-05	PASS	5349417047_SW2	1200	2.12E-05	PASS	-3.09E-07	-1%
5349417070_SW1	1200	5.63E-05	PASS	5349417070_SW1	1200	5.86E-05	PASS	2.32E-06	4%
5349417070_SW2	1200	1.70E-04	PASS	5349417070_SW2	1200	1.70E-04	PASS	-2.55E-07	0%

